

Application/Control No.	Applicant(s)/Patent under Reexamination	
	HESSE, CHRISTIAN	
Examiner	Art Unit	

Kin-Chan Chen

1765

SEARCHED					
Class	Subclass	Date	Examiner		
216	83	8/3/2007	ксс		
438	745				
	752				
	753				
	756				
438	757	8/3/2007	kcc		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East key words search USPAT, USP4-Pub Epo, JPO, Derwent IBM-7DB, huntersearch	8/3/2007	ксс		
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